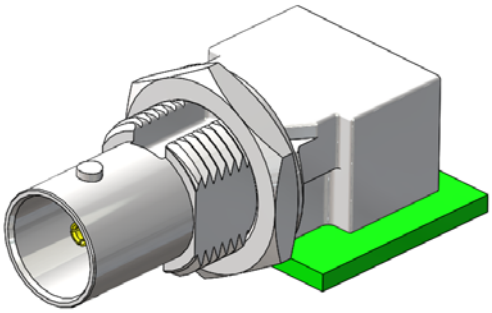
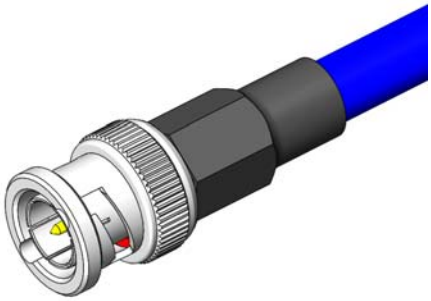
Project Number: Design Qualification Test Report	Tracking Code: 1539907_Report_Rev_1
Requested by: Alvin Wang	Date: 7/27/2018
Part #: BNC7T-J-P-GN-RA-BM1D/RFB6T-D4SP3-505050-0153	
Part description: BNC7T/RFB6T	Tech: Kason He
Test Start: 5/22/2018	Test Completed: 6/27/2018





DESIGN QUALIFICATION TEST REPORT

BNC7T/RFB6T
BNC7T-J-P-GN-RA-BM1D/RFB6T-D4SP3-505050-0153

REVISION HISTORY

DATA	REV.NUM.	DESCRIPTION	ENG
7/27/2018	**1**	**Initial Issue**	**KH**

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to IS0 10012-l and ANSI/NCSL 2540-1, as applicable.

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SCOPE

To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

1) All materials were manufactured in accordance with the applicable product specification.
2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
3) After soldering, the parts to be used for LLCR and DWV/IR testing were cleaned according to TLWI-0001.
4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
5) The automated procedure is used with aqueous compatible soldering materials.
6) Parts not intended for testing LLCR and DWV/IR are visually inspected and cleaned if necessary.
7) Any additional preparation will be noted in the individual test sequences.
8) Solder Information: Lead free
9) Samtec Test PCBs used: PCB-109089-TST/PCB-109090-TST

FLOWCHARTS

Thermal Aging

Group 1
BNC7T-J-P-GN-RA-BM1D
RFB6T-D4SP3-505050-0153
8 Assemblies

Step	Description
1.	Contact Gaps *Note: Signal and ground.*
2.	LLCR (1) *Note: Signal and ground.*
3.	Thermal Age (2)
4.	LLCR (1) Max Delta = 15 mOhm *Note: Signal and ground.*
5.	Contact Gaps *Note: Signal and ground.*

(1) LLCR = EIA-364-23
Open Circuit Voltage = 20 mV Max
Test Current = 100 mA Max

(2) Thermal Age = EIA-364-17
Test Condition = 4 (105°C)
Time Condition = B (250 Hours)

FLOWCHARTS Continued

Mating/Unmating/Durability

Group 1
BNC7T-J-P-GN-RA-BM1D
RFB6T-D4SP3-505050-0153
8 Assemblies

Step	Description
1.	Contact Gaps *Note: Signal and ground.*
2.	LLCR (2) *Note: Signal and ground.*
3.	Cycles Quantity = 500 Cycles *Note: By hand*
4.	Contact Gaps *Note: Signal and ground.*
5.	LLCR (2) Max Delta = 15 mOhm *Note: Signal and ground.*
6.	Thermal Shock (3)
7.	LLCR (2) Max Delta = 15 mOhm *Note: Signal and ground.*
8.	Humidity (1)
9.	LLCR (2) Max Delta = 15 mOhm *Note: Signal and ground.*

(1) Humidity = EIA-364-31
Test Condition = B (240 Hours)
Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)
Test Exceptions: ambient pre-condition and delete steps 7a and 7b

(2) LLCR = EIA-364-23
Open Circuit Voltage = 20 mV Max
Test Current = 100 mA Max

(3) Thermal Shock = EIA-364-32
Exposure Time at Temperature Extremes = 1/2 Hour
Method A, Test Condition = I (-55°C to +85°C)
Test Duration = A-3 (100 Cycles)

FLOWCHARTS Continued

IR/DWV

Pin-to-Ground

Group 1 BNC7T-J-P-GN-RA-BM1D RFB6T-D4SP3-505050-0153 2 Assemblies		Group 2 BNC7T-J-P-GN-RA-BM1D 2 Assemblies		Group 3 RFB6T-D4SP3-505050-0153 2 Assemblies		Group 4 BNC7T-J-P-GN-RA-BM1D RFB6T-D4SP3-505050-0153 2 Assemblies	
Step	**Description**	**Step**	**Description**	**Step**	**Description**	**Step**	**Description**
1.	DWV Breakdown (2)	1.	DWV Breakdown (2)	1.	DWV Breakdown (2)	1.	IR (4)
						2.	DWV at Test Voltage (1)
						3.	Thermal Shock (5)
						4.	IR (4)
						5.	DWV at Test Voltage (1)
						6.	Humidity (3)
						7.	IR (4)
						8.	DWV at Test Voltage (1)

(1) DWV at Test Voltage = EIA-364-20
Test Condition = 1 (Sea Level)
DWV test voltage is equal to 75% of the lowest breakdown voltage
Test voltage applied for 60 seconds

(2) DWV Breakdown = EIA-364-20
Test Condition = 1 (Sea Level)
DWV test voltage is equal to 75% of the lowest breakdown voltage
Test voltage applied for 60 seconds

(3) Humidity = EIA-364-31
Test Condition = B (240 Hours)
Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)
Test Exceptions: ambient pre-condition and delete steps 7a and 7b

(4) IR = EIA-364-21
Test Condition = 500 Vdc, 2 Minutes Max

(5) Thermal Shock = EIA-364-32
Exposure Time at Temperature Extremes = 1/2 Hour
Method A, Test Condition = I (-55°C to +85°C)
Test Duration = A-3 (100 Cycles)

FLOWCHARTS Continued

Mechanical Shock/Random Vibration/LLCR

Group 1
BNC7T-J-P-GN-RA-BM1D
RFB6T-D4SP3-505050-0410
8 Assemblies

Step	Description
1.	LLCR (1) *Note: Signal and ground.*
2.	Mechanical Shock (2)
3.	Random Vibration (3)
4.	LLCR (1) Max Delta = 15 mOhm *Note: Signal and ground.*

(1) LLCR = EIA-364-23
Open Circuit Voltage = 20 mV Max
Test Current = 100 mA Max

(2) Mechanical Shock = EIA-364-27
Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)
Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(3) Random Vibration = EIA-364-28
Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

Mechanical Shock/Random Vibration/Event Detection

Group 1
BNC7T-J-P-GN-RA-BM1D
RFB6T-D4SP3-505050-0410
8 Assemblies

Step	Description
1.	Nanosecond Event Detection (Mechanical Shock) (1)
2.	Nanosecond Event Detection (Random Vibration) (2)

(1) Nanosecond Event Detection (Mechanical Shock)
Use EIA-364-87 for Nanosecond Event Detection:
Test Condition = F (50 nanoseconds at 10 ohms)
Use EIA-364-27 for Mechanical Shock:
Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)
Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(2) Nanosecond Event Detection (Random Vibration)
Use EIA-364-87 for Nanosecond Event Detection:
Test Condition = F (50 nanoseconds at 10 ohms)
Use EIA-364-28 for Random Vibration:
Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

FLOWCHARTS Continued

Pull/Shear

Group 1
BNC7T-J-P-GN-RA-BM1D
RFB6T-D4SP3-505050-0153
5 Assemblies

Note: Push up on front connector shell perpendicular to shell axis.

Step	Description
1.	Connector Pull

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL SHOCK:

1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors.*
2) Test Condition 1: -55°C to +85°C
3) Test Time: ½ hour dwell at each temperature extreme
4) Number of Cycles: 100
5) All test samples are pre-conditioned at ambient.
6) All test samples are exposed to environmental stressing in the mated condition.

THERMAL:

1) EIA-364-17, *Temperature Life with or without Electrical Load Test Procedure for Electrical Connectors.*
2) Test Condition 4 at 105° C
3) Test Time Condition B for 250 hours.
4) All test samples are pre-conditioned at ambient.
5) All test samples are exposed to environmental stressing in the mated condition.

HUMIDITY:

1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors.*
2) Test Condition B, 240 Hours.
3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
4) All samples are pre-conditioned at ambient.
5) All test samples are exposed to environmental stressing in the mated condition.

MECHANICAL SHOCK (Specified Pulse):

1) Reference document: EIA-364-27, *Mechanical Shock Test Procedure for Electrical Connectors*
2) Test Condition C
3) Peak Value: 100 G
4) Duration: 6 Milliseconds
5) Wave Form: Half Sine
6) Velocity: 12.3 ft/s
7) Number of Shocks: 3 Shocks / Direction, 3 Axis (18 Total)

VIBRATION:

1) Reference document: EIA-364-28, *Vibration Test Procedure for Electrical Connectors*
2) Test Condition V, Letter B
3) Power Spectral Density: 0.04 G^2 / Hz
4) G 'RMS': 7.56
5) Frequency: 50 to 2000 Hz
6) Duration: 2.0 Hours per axis (3 axis total)

NANOSECOND-EVENT DETECTION:

1) Reference document: EIA-364-87, *Nanosecond-Event Detection for Electrical Connectors*
2) Prior to test, the samples were characterized to assure the low nanosecond event being monitored will trigger the detector.
3) After characterization it was determined the test samples could be monitored for 50 nanosecond events

MATING/UNMATING:

1) Reference document: EIA-364-13, *Mating and Unmating Forces Test Procedure for Electrical Connectors*.
2) The full insertion position was to within 0.003" to 0.004" of the plug bottoming out in the receptacle to prevent damage to the system under test.
3) One of the mating parts is secured to a floating X-Y table to prevent damage during cycling.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes.

LLCR:

1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.*
2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
    a. <= +5.0 mOhms: ---------- Stable
    b. +5.1 to +10.0 mOhms:---------- Minor
    c. +10.1 to +15.0 mOhms: ---------- Acceptable
    d. +15.1 to +50.0 mOhms: ---------- Marginal
    e. +50.1 to +2000 mOhms: ---------- Unstable
    f. >+2000 mOhms:---------- Open Failure

INSULATION RESISTANCE (IR):

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

1) PROCEDURE:
    a. Reference document: EIA-364-21, *Insulation Resistance Test Procedure for Electrical Connectors*.
    b. Test Conditions:
        i. Between Adjacent Contacts or Signal-to-Ground
        ii. Electrification Time 2.0 minutes
        iii. Test Voltage (500 VDC) corresponds to calibration settings for measuring resistances.
2) MEASUREMENTS:
3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 1000 megohms.

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

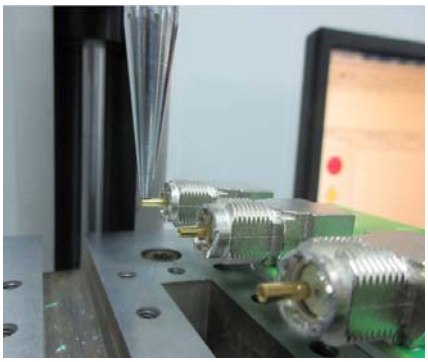
1) PROCEDURE:
    a. Reference document: EIA-364-20, *Withstanding Voltage Test Procedure for Electrical Connectors*.
    b. Test Conditions:
        i. Between Adjacent Contacts or Signal-to-Ground
        ii. Barometric Test Condition 1
        iii. Rate of Application 500 V/Sec
        iv. Test Voltage (VAC) until breakdown occurs
2) MEASUREMENTS/CALCULATIONS
    a. The breakdown voltage shall be measured and recorded.
    b. The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
    c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes.

PULL SHEAR:

push perpendicular on the center contact. Record that data when the center contact was abscission.



90° push

0° push

RESULTS

PULL SHEAR:

- **90° push**
  - **Min---------- 1.84 kg**
  - **Max ---------- 2.31 kg**
- **0° push**
  - **Min---------- 5.74 kg**
  - **Max ---------- 7.25 kg**

Insulation Resistance minimums, IR

- **Initial**
  - **Mated----------45000 Meg Ω ---------- Passed**
  - **Unmated ----------45000 Meg Ω ---------- Passed**
- **Thermal Shock**
  - **Mated----------45000 Meg Ω ---------- Passed**
  - **Unmated ----------45000 Meg Ω ---------- Passed**
- **Humidity**
  - **Mated----------45000 Meg Ω ---------- Passed**
  - **Unmated ----------45000 Meg Ω ---------- Passed**

Dielectric Withstanding Voltage minimums, DWV

- **Minimums**
  - **Breakdown Voltage---------- 2883 VAC**
  - **Test Voltage ---------- 2165 VAC**
  - **Working Voltage ----------720 VAC**

Pin to Closest Metallic Hardware

- **Initial DWV ----------Passed**
- **Thermal DWV----------Passed**
- **Humidity DWV----------Passed**

RESULTS Continued

LLCR Thermal Aging Group (16 LLCR test points)

Signal

- **Initial ---------- 7.01 mOhms Max**

Ground Pin:

- **Initial ---------- 1.77 mOhms Max**
- **Thermal**
  - **<= +5.0 mOhms ---------- 16 Points ---------- Stable**
  - **+5.1 to +10.0 mOhms ---------- 0 Points ---------- Minor**
  - **+10.1 to +15.0 mOhms ---------- 0 Points ---------- Acceptable**
  - **+15.1 to +50.0 mOhms ---------- 0 Points ---------- Marginal**
  - **+50.1 to +2000 mOhms ---------- 0 Points ---------- Unstable**
  - **>+2000 mOhms ---------- 0 Points ---------- Open Failure**

LLCR Mating/Unmating Durability Group (16 LLCR test points)

Signal

- **Initial ---------- 7.00 mOhms Max**

Ground

- **Initial ---------- 1.85 mOhms Max**
- **Durability, 500 Cycles**
  - **<= +5.0 mOhms ---------- 16 Points ---------- Stable**
  - **+5.1 to +10.0 mOhms ---------- 0 Points ---------- Minor**
  - **+10.1 to +15.0 mOhms ---------- 0 Points ---------- Acceptable**
  - **+15.1 to +50.0 mOhms ---------- 0 Points ---------- Marginal**
  - **+50.1 to +2000 mOhms ---------- 0 Points ---------- Unstable**
  - **>+2000 mOhms ---------- 0 Points ---------- Open Failure**
- **Thermal Shock**
  - **<= +5.0 mOhms ---------- 16 Points ---------- Stable**
  - **+5.1 to +10.0 mOhms ---------- 0 Points ---------- Minor**
  - **+10.1 to +15.0 mOhms ---------- 0 Points ---------- Acceptable**
  - **+15.1 to +50.0 mOhms ---------- 0 Points ---------- Marginal**
  - **+50.1 to +2000 mOhms ---------- 0 Points ---------- Unstable**
  - **>+2000 mOhms ---------- 0 Points ---------- Open Failure**
- **Humidity**
  - **<= +5.0 mOhms ---------- 16 Points ---------- Stable**
  - **+5.1 to +10.0 mOhms ---------- 0 Points ---------- Minor**
  - **+10.1 to +15.0 mOhms ---------- 0 Points ---------- Acceptable**
  - **+15.1 to +50.0 mOhms ---------- 0 Points ---------- Marginal**
  - **+50.1 to +2000 mOhms ---------- 0 Points ---------- Unstable**
  - **>+2000 mOhms ---------- 0 Points ---------- Open Failure**

RESULTS Continued

LLCR Shock & Vibration (16 LLCR test points)

Signal Pin

- **Initial ---------- 13.04 mOhms Max**

Ground Pin

- **Initial ----------4.83 mOhms Max**
- **Shock &Vibration**
  - **<= +5.0 mOhms ---------- 16 Points ---------- Stable**
  - **+5.1 to +10.0 mOhms ----------0 Points ---------- Minor**
  - **+10.1 to +15.0 mOhms ----------0 Points ---------- Acceptable**
  - **+15.1 to +50.0 mOhms ----------0 Points ---------- Marginal**
  - **+50.1 to +2000 mOhms----------0 Points ---------- Unstable**
  - **>+2000 mOhms----------0 Points ---------- Open Failure**

Mechanical Shock & Random Vibration:

- **Shock**
  - **No Damage---------- ---------- Pass**
  - **50 Nanoseconds---------- ---------- Pass**
- **Vibration**
  - **No Damage---------- ---------- Pass**
  - **50 Nanoseconds---------- ---------- Pass**

DATA SUMMARIES

Pull Shear:

90° push

	Force (Kg)
Minimum	**1.84**
Maximum	2.31
Average	2.08

0° push

	Force (Kg)
Minimum	**5.74**
Maximum	7.25
Average	6.69

INSULATION RESISTANCE (IR):

	Pin to Closest Metallic Hardware		
	Mated	Unmated	Unmated
Minimum	**BNC7T/RFB6T**	**BNC7T**	**RFB6T**
Initial	45000	45000	45000
Thermal	45000	45000	45000
Humidity	45000	45000	45000

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

Voltage Rating Summary	
Minimum	**BNC7T/RFB6T**
Break Down Voltage	2883
Test Voltage	2165
Working Voltage	720

Pin to Closest Metallic Hardware	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

DATA SUMMARIES Continued

LLCR Thermal Aging Group

1) A total of 16 points were measured.
2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.*
3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
   a. <= +5.0 mOhms:----------Stable
   b. +5.1 to +10.0 mOhms: ----------Minor
   c. +10.1 to +15.0 mOhms:----------Acceptable
   d. +15.1 to +50.0 mOhms:----------Marginal
   e. +50.1 to +2000 mOhms----------Unstable
   f. >+2000 mOhms: ----------Open Failure

LLCR Measurement Summaries by Pin Type				
Date	5/22/2018	6/5/2018		
Room Temp (Deg C)	24	23		
Rel Humidity (%)	58	54		
Technician	Kason He	Kason He		
mOhm values	**Actual Initial**	**Delta Thermal**	**Delta**	**Delta**
	Pin Type 1: Signal			
Average	6.91	0.04		
St. Dev.	0.05	0.02		
Min	6.81	0.01		
Max	7.01	0.09		
Summary Count	8	8		
Total Count	8	8		
	Pin Type 2: Ground			
Average	1.66	0.26		
St. Dev.	0.06	0.25		
Min	1.56	0.05		
Max	1.77	0.86		
Summary Count	8	8		
Total Count	8	8		

LLCR Delta Count by Category						
	Stable	**Minor**	**Acceptable**	**Marginal**	**Unstable**	**Open**
mOhms	**<=5**	**>5 & <=10**	**>10 & <=15**	**>15 & <=50**	**>50 & <=1000**	**>1000**
Thermal	**16**	**0**	**0**	**0**	**0**	**0**

DATA SUMMARIES Continued

LLCR Mating/Unmating Durability Group

1). A total of 16 points were measured.
2). EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.*
3). A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
4). The following guidelines are used to categorize the changes in LLCR as a result from stressing.
   a. <= +5.0 mOhms: ----------Stable
   b. +5.1 to +10.0 mOhms: ----------Minor
   c. +10.1 to +15.0 mOhms: ----------Acceptable
   d. +15.1 to +50.0 mOhms: ----------Marginal
   e. +50.1 to +2000 mOhms ----------Unstable
   f. > +2000 mOhms: ----------Open Failure

LLCR Measurement Summaries by Pin Type				
Date	5/22/2018	6/5/2018	6/15/2018	6/27/2018
Room Temp (Deg C)	24	24	24	24
Rel Humidity (%)	54	54	53	54
Technician	Kason He	Kason He	Kason He	Kason He
mOhm values	**Actual Initial**	**Delta 500 Cycles**	**Delta Therm Shck**	**Delta Humidity**
	Pin Type 1: Signal			
Average	6.93	0.12	0.04	0.08
St. Dev.	0.04	0.10	0.03	0.10
Min	6.88	0.00	0.01	0.01
Max	7.00	0.29	0.08	0.34
Summary Count	8	8	8	8
Total Count	8	8	8	8
	Pin Type 2: Ground			
Average	1.70	0.22	1.60	1.41
St. Dev.	0.08	0.36	0.83	0.85
Min	1.59	0.01	0.46	0.39
Max	1.85	1.17	3.21	2.83
Summary Count	8	8	8	8
Total Count	8	8	8	8

LLCR Delta Count by Category						
	Stable	**Minor**	**Acceptable**	**Marginal**	**Unstable**	**Open**
mOhms	**<=5**	**>5 & <=10**	**>10 & <=15**	**>15 & <=50**	**>50 & <=1000**	**>1000**
500 Cycles	**16**	**0**	**0**	**0**	**0**	**0**
Therm Shck	**16**	**0**	**0**	**0**	**0**	**0**
Humidity	**16**	**0**	**0**	**0**	**0**	**0**

DATA SUMMARIES Continued

LLCR Shock &Vibration:

1). A total of 16 points were measured.

2). EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets.*

3). The following guidelines are used to categorize the changes in LLCR as a result from stressing.

a. <= +5.0 mOhms: ---------- Stable
b. +5.1 to +10.0 mOhms: ---------- Minor
c. +10.1 to +15.0 mOhms: ---------- Acceptable
d. +15.1 to +50.0 mOhms: ---------- Marginal
e. +50.1 to +2000 mOhms ---------- Unstable
f. >+2000 mOhms: ---------- Open Failure

	LLCR Measurement Summaries by Pin Type			
Date	7/11/2018	7/13/2018		
Room Temp (Deg C)	23	23		
Rel Humidity (%)	46	41		
Technician	Aaron Mckim	Aaron Mckim		
mOhm values	**Actual Initial**	**Delta Shock-Vib**	**Delta**	**Delta**
	Pin Type 1: Ground			
Average	4.24	0.28		
St. Dev.	0.26	0.17		
Min	3.95	0.04		
Max	4.83	0.68		
Summary Count	8	8		
Total Count	8	8		
	Pin Type 2: Signal			
Average	12.91	0.05		
St. Dev.	0.10	0.04		
Min	12.71	0.00		
Max	13.04	0.12		
Summary Count	8	8		
Total Count	8	8		

LLCR Delta Count by Category						
	Stable	**Minor**	**Acceptable**	**Marginal**	**Unstable**	**Open**
mOhms	**<=5**	**>5 & <=10**	**>10 & <=15**	**>15 & <=50**	**>50 & <=1000**	**>1000**
Shock-Vib	**16**	**0**	**0**	**0**	**0**	**0**

Nanosecond Event Detection:

Shock and Vibration Event Detection Summary	
Contacts tested	16
Test Condition	C, 100g's, 6ms, Half-Sine
Shock Events	0
Test Condition	V-B, 7.56 rms g
Vibration Events	0
Total Events	0

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: HZ-TCT-01
Description: Normal force analyzer
Manufacturer: Mecmesin Multitester
Model: Mecmesin Multitester 2.5-i
Serial #: 08-1049-04
Accuracy: Last Cal: 4/25/2018, Next Cal: 4/24/2019

Equipment #: HZ-OV-01
Description: Oven
Manufacturer: Huida
Model: CS101-1E
Serial #: CS101-1E-B
Accuracy: Last Cal: 12/12/2017, Next Cal: 12/11/2018

Equipment #: HZ-THC-01
Description: Humidity transmitter
Manufacturer: Thermtron
Model: SM-8-8200
Serial #: 38846
Accuracy: Last Cal: 2/27/2018, Next Cal: 2/26/2019

Equipment #: HZ-TSC-01
Description: Vertical Thermal Shock Chamber
Manufacturer: Cincinnatti Sub Zero
Model: VTS-3-6-6-SC/AC
Serial #: 10-VT14994
Accuracy: See Manual
… Last Cal: 06/27/2018, Next Cal: 06/26/2019

Equipment #: DG-HPM-02
Description: Hipot Safety Tester
Manufacturer: Vitrek
Model: V73
Serial #: 025866
Accuracy:
… Last Cal: 10/20/2017, Next Cal: 10/19/2018

Equipment #: HZ-MO-05
Description: Micro-ohmmeter
Manufacturer: Keithley
Model: 3706
Serial #: 1285188
Accuracy: Last Cal: 11/14/2017, Next Cal: 11/13/2018

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: SVC-01
Description: Shock & Vibration Table
Manufacturer: Data Physics
Model: LE-DSA-10-20K
Serial #: 10037
Accuracy: See Manual
… Last Cal: 04/22/2016, Next Cal: 04/22/2019

Equipment #: ACLM-01
Description: Accelerometer
Manufacturer: PCB Piezotronics
Model: 352C03
Serial #: 115819
Accuracy: See Manual
… Last Cal: 07/18/2017, Next Cal: 07/18/2018

Equipment #: ED-03
Description: Event Detector
Manufacturer: Analysis Tech
Model: 32EHD
Serial #: 1100604
Accuracy: See Manual
… Last Cal: 10/31/2017, Next Cal: 10/31/2018

Equipment #: MO-04
Description: Multimeter /Data Acquisition System
Manufacturer: Keithley
Model: 2700
Serial #: 0798688
Accuracy: See Manual
… Last Cal: 09/11/2017, Next Cal: 09/11/2018